# STATISTICAL LEARNING THEORY

In these notes we will cover basic performance guarantees for classification.

Let  $(X_1, Y_1), \dots, (X_n, Y_n)$  be iid realizations of  $(X_1, Y_1)$ , where  $X \in \mathbb{R}^d$ ,  $Y \in \{0, 1\}$ .

Let  $f: \mathbb{R}^d \to \{0,1\}$  be a classifier. Define the risk

$$R(f) := Pr \{ f(x) \neq y \}$$

$$= E \left[ 1_{\{f(x) \neq y\}} \right]$$

and the empirical risk

$$\hat{R}_{n}(f) := \frac{1}{n} \sum_{i=1}^{n} 1_{\{f(X_{i}) \neq Y_{i}\}}$$

of f. Notice

# Hoeffding's Inequality

Theorem Let  $Z_i$ , ...,  $Z_n$  be independent, bounded  $RV_s$  such that  $Pr\{Z_i \in [a_i,b_i]\} = 1$ . Set  $S_n = \sum_{i=1}^n Z_i$ . Then Vt > 0,

$$\Pr \left\{ S_{n} - ES_{n} \ge t \right\} \le e^{-2t^{2}/\sum_{i=1}^{n} (b_{i} - a_{i})^{2}}$$

and

Remarks

- . We may combine the two statements to obtain  $Pr\{|S_n-ES_n|\geq t\}\leq 2e^{-2t^2/\sum_{i=1}^n \left(b_i-a_i\right)^2}$
- In the special case where  $Z_i$  are iid Bernoulli(p), then  $b_i = 1$ ,  $a_i = 0$ , and  $S_n$  is binom (n, p), and we recover Chernoff's bound:

Hoeffding's is an example of a concentration inequality.

#### Proof

LEMMA 2.1. Let **V** be a random variable with EV = 0,  $a \le V \le b$ . Then for s > 0:

$$\mathbb{E}\{e^{sV}\} \le e^{s^2(b-a)^2/8}.$$

PROOF. Note that by convexity of the exponential function

$$e^{s\mathbf{r}} \le \frac{\mathbf{r}-a}{b-a}e^{sb} + \frac{b-\mathbf{r}}{b-a}e^{sa}$$
 for  $a \le \mathbf{v} \le b$ .

Exploiting EV = 0, and introducing the notation p = -a/(b-a), we get

$$\mathbf{E}\{e^{sV}\} \le \frac{b}{b-a}e^{sa} - \frac{a}{b-a}e^{sb}$$

$$= (1-p+pe^{s(b-a)})e^{-ps(b-a)}$$

$$\stackrel{\text{def}}{=} e^{\phi(u)},$$

where u = s(b-a) and  $\phi(u) = -pu + \log(1-p+pe^u)$ . But by straightforward calculation it is easy to see that the derivative of  $\phi$  is

$$\phi'(u) = -p + \frac{p}{p + (1-p)e^{-u}},$$

and therefore  $\phi(0) = \phi'(0) = 0$ . Moreover

$$\phi''(u) = \frac{p(1-p)e^{-u}}{(p+(1-p)e^{-u})^2} \le \frac{1}{4}.$$

Thus, by Taylor's theorem, for some  $\theta \in [0, u]$ :

$$\phi(u) = \phi(0) + u\phi'(0) + \frac{u^2}{2}\phi''(\theta) \le \frac{u^2}{8} = \frac{s^2(b-a)^2}{8}. \quad \Box$$

Devroye and Lugosi,

Combinatorial Methods
in Density Estimation,

Springer 2001.

Lemma] (Markov's Inequality) If u is a nonnegative random variable, then for all t > 0,  $Pr\{u \ge t\} \le \frac{Eu}{t}$ Proof:  $Pr\{u \ge t\} = E[1_{\{u \ge t\}}]$   $= E[\frac{u}{t} = 1_{\{u \ge t\}}]$   $= \frac{1}{t} E[u = 1_{\{u \ge t\}}]$ 

Now, for any S>O, we have Pr { Sn - Esn > t } = Pr { s(Sn - Esn) > st} = Pr {e s(sn-Esn) > est } Markov's lineguality ≤ e-st. E[es(Sn-ESn)]  $= e^{-st} \begin{bmatrix} \int e^{-st} \left( Z_i - EZ_i \right) \right]$ = e = [ ] e s.(Z;-EZ;)]  $= e^{-st} \hat{T} \left[ e^{s(Z_i - EZ_i)} \right]$ (in de penolence)

 $= e^{-2t^2/\frac{1}{2}(b_i-a_i)^2} \qquad (S = 4t/\Sigma(b_i-a_i)^2)$ 

Returning to classification, by Hoeffding's / Chesnoll's bound we know that for any classifier f

$$\Pr\left\{\hat{R}_n(f) \geqslant R(f) + \epsilon\right\} \leq e^{-2n\epsilon^2},$$

which -> 0 exponentially fast as h-> 00 ( Fixed).

### Uniform Deviation Bounds

In reality, we don't know the best classifier a priori, one way to overcome this is to prove a performance guarantee that holds for many classifiers simultaneously.

Theorem | For any E>0,

$$\Pr\left\{ \max_{f \in \mathcal{F}} \left| \hat{\mathcal{R}}_{n}(f) - \mathcal{R}(f) \right| \geq \epsilon \right\} \leq 2Me^{-2n\epsilon^{2}}$$

Proof: 
$$= Pr \left\{ \text{ for some } m, |\hat{R}_n(f_m) - R(f)| \ge \epsilon \right\}$$

$$\leq \sum_{m=1}^{m} \Pr \left\{ |\hat{R}_n(f_m) - R(f_m)| \geq \epsilon \right\}$$
 (union bound)

### Empirical Risk Minimization

Let's two this result into a classification rule with a performance guarantee.

Denote

$$\mathcal{R}(\mathcal{F}) = \inf_{f \in \mathcal{F}} \mathcal{R}(f)$$

and define the rule

$$\hat{f}_n = \underset{f \in \mathcal{F}}{\text{arg min}} \hat{\mathcal{R}}_n(f)$$

Theorem Let  $\epsilon > 0$ . With probability at least  $1 - 2Me^{-2n\epsilon^2}$ ,

$$R(\hat{f}_n) \leq R(\mathcal{F}) + 2\epsilon$$

Proof: With prob = 1-2Me-znez, we have

sup  $|\hat{R}_n(f) - R(f)| < \epsilon$ . In this event, for any f,  $f \in \mathcal{F}$ 

$$R(\hat{f}_n) \leq \hat{R}_n(\hat{f}_n) + \epsilon$$

$$= \hat{R}_n(\hat{f}_n) + \epsilon \qquad \left( \text{def of } \hat{f}_n \right)$$

$$\leq R(f) + \epsilon$$

Since f is arbitrary, the result follows.

Key point ! The above result is distribution free, meaning it makes no assumptions on the distribution of (X,Y).

Note that the proof did not depend on I being finite, only on the existence of a uniform deviation bound for J. Such bounds also exist in cases where J is infinite.

## VC Bounds

Let I now be an arbitrary collection of classifiers, perhaps uncountably infinite.

Definition Given points x1,..., xn ∈ Rd, let Ny (x1,...,xn) be the number of distinct vectors  $(f(x_i), ..., f(x_n)) \in \{0,1\}^n$ as franges over F.

Now define the nth shatter coefficient of F  $S(\mathcal{F},n) = \max_{\chi_1,\ldots,\chi_n} \mathcal{N}_{\mathcal{F}}(\chi_1,\ldots,\chi_n).$ 

Cleary  $S(\mathcal{F},n) \leq 2^n$  for every n. If  $S(\mathcal{F},n)$   $= 2^n$ , then  $N_{\mathcal{F}}(x_1,...,x_n) = 2^n$  for some  $x_1,...,x_n$ , and we say  $\mathcal{F}$  shatters  $x_1,...,x_n$ .

Definition Assume  $|\mathcal{F}| \ge 1$ . The largest k such that  $S(\mathcal{F},k) = 2^k$  is called the Vapnik-Chenomenkis (VC) obinension of  $\mathcal{F}$ . If no such k exists, we set  $VCdim(\mathcal{F}) = \infty$ .

If can be shown that if  $\mathcal{F}$  has VC ohim.  $V \ge 2$ , then Vn,

 $S(3,n) \leq n^{V}$ 

The following result is alue to Vapnik + Cherumenkis.

Theorem | For any & > 0

 $P \left\{ \sup_{f \in \mathcal{F}} |\hat{R}_{n}(f) - R(f)| > \epsilon \right\} \leq 85(\mathcal{F}_{n})e^{-n\epsilon^{2}/32}$ 

Proof: See Devroye, Györfi, and Lugosi, A Probabilistic Theory of Pattern Recognition.

Again, this is a distribution-free result.

Corollary For empirical risk minimimization,

 $P\left\{R(\hat{f}_{n}) \geq \inf_{f \in \mathcal{F}} R(f) + 2\epsilon\right\} \leq 85(\mathcal{F}_{n})e^{-n\epsilon^{2}/32}$ 

[Cay Point] If  $VCdim(\Im) = V < \infty$ , and we use  $S(\Im,n) \leq n^V$ , then we see that the "failure probability" is bounded by  $8n^V = \frac{n^2}{32}$ 

which -> 0 exponentially fast as n-> 0 (& fixed).

So which I have Binite VC dimension?

# VC Classes

Rectangles Suppose I is the collection of classifiers of the form  $1_{5x \in R}$ , where R ranges over all rectangles in  $\mathbb{R}^d$ .

What is the VC dim. of  $\mathbb{F}$ ?

Claim: V = 2d.

Need to show (a) I 2d points shattened by F, (b) F cannot shatter any collection of > 2d points.

For (a), take the 2d points

(1,0,...,0), (0,1,0,...,0), ..., (0,...,0,1) (-1,0,...,0), (0,-1,0,...,0), ..., (0,...,0,-1)

For (b), consider any set of > 2d points.

Then there exists a subset of at most 2d "extreme" points, that are the min or max along at least on dimension. Clearly no R contains all these points but not the others.

d=2

The following general result allows us to bound VC dims for many classes.

Theorem 1 Let G be a vector space of functions with dim (G) = r. If  $\mathcal{F}$  is the set of classifiers of the form  $x \mapsto 1 \leq g(x) \geq 0 \leq r$ 

then VCdim (F) < r.

PROOF. It suffices to show that no set of size m=1+r can be shattered by sets of the form  $\{x:g(x)\geq 0\}$ . Fix m arbitrary points  $x_1,\ldots,x_m$ , and define the linear mapping  $L:\mathcal{G}\to\mathcal{R}^m$  as

← DGL

$$L(g) = (g(x_1), \ldots, g(x_m)).$$

Then the image of  $\mathcal{G}$ ,  $L(\mathcal{G})$ , is a linear subspace of  $\mathbb{R}^m$  of dimension not exceeding the dimension of  $\mathcal{G}$ , that is, m-1. Then there exists a nonzero vector  $\gamma = (\gamma_1, \ldots, \gamma_m) \in \mathbb{R}^m$ , that is orthogonal to  $L(\mathcal{G})$ , that is, for every  $g \in \mathcal{G}$ 

$$\gamma_1 g(x_1) + \ldots + \gamma_m g(x_m) = 0.$$

We can assume that at least one of the  $\gamma_i$ 's is negative. Rearrange this equality so that terms with nonnegative  $\gamma_i$  stay on the left-hand side:

$$\sum_{i:y_i>0} \gamma_i g(x_i) = \sum_{i:y_i<0} -\gamma_i g(x_i).$$

Now, suppose that there exists a  $g \in \mathcal{G}$  such that the set  $\{x : g(x) \geq 0\}$  picks exactly the  $x_i$ 's on the left-hand side. Then all terms on the left-hand side are nonnegative, while the terms on the right-hand side must be negative, which is a contradiction, so  $x_1, \ldots, x_m$  cannot be shattered, and the proof is completed.  $\square$ 

Linear Classifiers

Suppose  $\mathcal{F} = \text{all } \mathcal{G} \text{ of the form } f(x) = \text{sign} \{w^{T}x + b\},\ w \in \mathbb{R}^d, b \in \mathbb{R}.$ 

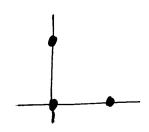
What is V?

Claim: V = d+1.

By the above theorem, we have  $V \leq d+1$ , taking G to be the space spanned by

$$\varphi^{(1)}(x) = \chi^{(1)}, \dots, \varphi^{(a)}(x) = \chi^{(a)}, \varphi^{(a+1)}(x) = 1$$

Furthernure, 7 shaffers



Exercise | Determine the W dimension of

· J = all classifies of the form

$$f(x) = 1$$

$$\{x \in B(a,b)\}$$

where  $B(a,b) = \{x: ||x-a|| \le b \}, a \in \mathbb{R}^q, b \in \mathbb{R}$ 

· J = all classifiers of the form

$$f(x) = 1 \{x \in C\}$$

where C is a convex polygon in R2.

### Neural Networks

For neural networks with k hidden unifs and w tunable weights, Kanpinski and Marintyre (1994) showed

 $V \leq \frac{k w (k w - 1)}{2} + w (1 + 2k) + w (1 + 3k) \log (3w + 6kw + 3),$  assuming the standard sigmoid function.

### Summary

The above results tell us performance guarantees for many class. For example, for the empirical risk minimizing linear classifier for

Unfortunately, empirical risk minimization is (provably) not computational beasible over most classes of interest. Therefore these results are largely of theoretical importance. Furthermore, the bounds tend to be very boose (often > 1) in practice.

### PAC Learning and Sample Complexity

An algorithm  $\widehat{f_n}$  is said to be an  $(\epsilon, \delta)$ -learning algorithm for  $\mathcal{F}$  if  $\mathcal{F}$  a function  $\mathcal{N}(\epsilon, \delta)$  such that,  $\forall \epsilon, \delta \neq 0$ ,  $\forall \epsilon, \delta \neq 0$ ,  $\forall \epsilon, \delta \neq 0$  and  $\forall \epsilon, \delta \neq 0$  and  $\forall \epsilon, \delta \neq 0$  for all distributions of (x, y).

#### Terminology

- · N(E, S) is called the sample complexity
- · I is said to be uniformly learnable
- · În is said to be "probably approximately correct" (PAC)

We have seen that if  $VCdim(\mathcal{F}) < \omega$ , then

- · F is uniformly learnable
- · ERM is an (E,S)-learning algorithm
- $N(\epsilon, \delta) = O\left(\max \left\{ \frac{V}{\epsilon^2} \log \frac{V}{\epsilon^2}, \frac{1}{\epsilon^2} \log \frac{1}{\delta} \right\} \right)$   $\left\{ \frac{1}{8} e^{-n\epsilon^2/128} \leq \delta \right\}$

Key A. nRn(f) ~ binon (n, R(f))